

**Reliability Data Summary:**

QV DEVICE NAME: K22F

PACKAGE: iBGA

Test	Specification	Condition	Interval	Results
PC	JESD22 A113 J-STD-020	MSL 3 @ 260 °C		0/720
HAST	JESD22 A110	130°C, 85% RH, 18.8psig, bias	96 hrs	0/240
uHAST	JESD22 A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs	0/240
TC	JESD22 A104	Ta= -55°C to + 125°C	1000 cyc	0/240
HTSL	JESD22 A103	Ta= 150°C	1008 hrs	0/240
LTSL	JESD22 A103	Ta= -40°C	1008 hrs	0/240
HTOL	JESD22 A108	Ta=105°C, 100 % max rated Vcc	1008hrs	0/320
ELFR	AEC-Q100-008	Ta=125°C, 100 % max rated Vcc	48 hrs	0/3270
WBS	AEC-Q100-001	Wire Bond Shear Test: Cpk >1.67		0/369
WBP	Mil-Std-883 Meth 2011	Wire Bond Pull: Cpk>1.67		0/369
SD	J-STD-002or JESD22 B102	Solderability		0/15
PD	JESD22 B100,B108	Physical Dimension: Critical Cpk>1.67		0/30
EM	JP001	Electromigration		Pass
TDDDB	JP001	Time Dependent Dielectric Breakdown		Pass
HCI	JP001	Hot Carrier Injection		Pass
NBTI	JP001	Negative Bias Temperature Instability		Pass
SM	JP001	Stress Migration		Pass
TEST	User/Supplier Spec	Pre and Post Stress Electrical Test		Pass
HBM	AEC-Q100-002	Electrostatic Discharge, Human Body Model/ Machine Model: (Test @ R/H)	> 2000V	Pass
CDM	AEC-Q100-011	Electrostatic Discharge, Charge Device Model: (Test @ R/H)	> 750V	Pass
LU	AEC-Q100-004	Latch-up: (Test @R/H)		Pass
ED	AEC-Q100-009	Elect. Distribution: (Test @ C/ R/ H)		Pass
CHAR	AEC Q003	Characterization		Pass
PAT	AEC Q001	Process Average Testing		Pass
SBA	AEC Q002	Statistical Bin/Yield Analysis		Pass

The qualification results show no fails. Reliability test results are available upon request.

Electrical Characteristic Summary:

Electrical characteristics are not impacted.

List of Affected Standard Parts:

Part Number	Qualification Vehicle
ASX340AT3C00XPED0-DPBR	K22F
ASX340AT3C00XPED0-KP-DPBR	